## Claims

## > IN THE CLAIMS

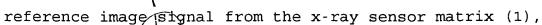
* 1	1.	An x-ray examination apparatus comprising
$\mu^{\kappa}$ <sup>2</sup>		- an x-ray image sensor matrix (1) for deriving an
<sup>3</sup> 0, <sup>3</sup>		initial image signal from an x-ray image,
4		- a correct on unit (2) for deriving a corrected image
5		signal from the initial image signal
6		
		characterised in that
100 June 100		- the correction unit (2) includes a
10/1 (N		- memory (3) for storing correction values and
11:		- an arithmetic whit (4) for computing signal levels of
12, =		the corrected image signal from signal levels of the initial
12,		image signal and at least some of said correction values.
1	2.	An x-ray examination apparatus as claimed in Claim 1,
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2	char	acterised in that
3		- the correction unit (2) includes a selection unit (5)
4		for selecting correction values from the memory (3) on the
5		basis of exposure parameters.
1 .	3.	An x-ray examination apparatus as claimed in Claim 2,

characterised in that

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- the correction unit (2) is arranged to generate a



- the selection unit (5) is arranged to select the correction values on the basis of the reference image signal.
- 4. An x-ray examination apparatus as claimed in any one of the preceding Claims, characterised in that
  - the arithmetic unit (4) is arranged to compute correction values from stored correction values.
- 5. An x-ray examination apparatus as claimed in Claim 4, characterised in that
  - the arithmetic unit (4) is arranged to interpolate said computed correction values between stored correction values.

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